

EMC TEST REPORT

Project No.	LBE20130383	Revision No.	NONE
FCC ID	A3LLS20C300		
Applicant	Name of organization	Samsung Electronics Co., Ltd.	
	Address	18600 Broad wick St. Rancho Dominguez CA 90220	
	Date of application	January 16,2013	
EUT Equipment Under Test	Type of device	Class B personal computers and peripherals	
	Equipment authorization	<input type="checkbox"/> Declaration of Conformity <input checked="" type="checkbox"/> Certification <input type="checkbox"/> Verification	
	Kind of product	LCD MONITOR	
	Model No.	LS20C3**	
		(The character “*” may be 0-9, A-Z or blank, it means different color or outlook)	
	Variant Model No.	None	
Manufacturer	Tianjin Samsung Electronics Co., LTD. Weisi Rd. Micro-Electronic Industrial Park, Jingang Rd. Xiqing Dist, Tianjin,300385 China		
Applied Standards		FCC Part 15, Subpart B class B	
		ANSI C63.4-2009	
Test period		January 21,2013- January 24,2013	
Issue date		January 31,2013	

Test result : Complied

The equipment under test has found to be compliant with the applied standards.
 (Refer to the attached test result for more detail.)

Tested by : Hesong Jin



Reviewed by : Xiao Li



The test results in this report only apply to the tested sample. This report must not be reproduced, except in full, without written permission from CSQAL



TSEC Wei 4 Road, Microelectronics Industrial Park, Jingang High way, Tianjin, China
 Tel: 86 22 23961234, Fax: 86 22 23961234-5214



According to Sec. 2.1077, 47 CFR of the FCC Rules.

This device complies with Part 15 of the FCC Rules. Operation is subject to the following two conditions: (1) This device may not cause harmful interference, and (2) This device must accept any interference received, including interference that may cause undesired operation.

Equipment EUT Type	Class B personal computers and peripherals
Kind of product	LCD Monitor
Trade Name	Samsung Electronics
Model	LS20C3** (The character “*” may be 0-9, A-Z or blank, it means different color or outlook)
Applied Rules	FCC Part 15, Subpart B Class B
	ANSI C63.4-2009
Manufacturer	Tianjin Samsung Electronics Co., LTD. Weisi Rd. Micro-Electronic Industrial Park, Jingang Rd. Xiqing Dist, Tianjin,300385 China

We hereby *declare that* the equipment bearing the trade name and model number specified above was tested conforming to the applicable FCC Rules under the most accurate measurement standards possible, and that all the necessary steps have been taken and are in force to assure that production units of the same equipment will continue to comply with the Commission's requirements.


U.S. RESPONSIBLE PARTY	Samsung Electronics America QA Lab 18600 Broad wick St. Rancho Dominguez CA 90220
CONTACT PERSON	 <u>Mr. Peter Ra, Manager</u> E-Mail : raaaa@samsung.com Tel : 1-310-900-5250 Fax : 1-310-537-5500

Table of contents

1. Summary of test results

1.1 Emission

2. General Information

2.1 Test facility

3. Test configuration

3.1 Test Peripherals

3.2 EUT operating mode

3.3 Details of Sampling

3.4 Used cable description

3.5 EUT Description

3.6 Description of the EUT exercising method

3.7 Measurement uncertainty

4. Result of individual tests

4.1 Conducted disturbance

4.2 Radiated disturbance

Appendix – EUT photography

1. Summary of test results

The EUT has been tested according to the following specifications:

Applied	Test type	Applied standard	Result	Remarks
<input checked="" type="checkbox"/>	Conducted Disturbance	FCC Part 15 Subpart B	Complied	Meets Class B Limit
<input checked="" type="checkbox"/>	Radiated Disturbance		ANSI C63.4-2009	Complied

- Note : These results are deemed satisfactory evidence of compliance with ICES-003 of the Canadian Interference-Causing Equipment Regulations.

2. General Information

2.1 Test facility

The following firm has submitted the information required by Section 2.948 of the FCC Rules for measuring devices subject to Certification under Parts 15 & 18. The FCC takes no responsibility regarding the capability of this firm for performing the required measurements. Accordingly, this firm should not advertise or otherwise imply FCC approval of CSQAL.

CHINA SAMSUNG QUALITY ASSURANCE LABORATORY is LOCATED ON Block D, 17 - 19, Wei 4 Road, Microelectronics Industrial Park, Jingang Highway, Tianjin China.

Registration Number: 745769

E-mail Address: xiao.li@samsung.com

Phone Number: 86-22-2396-1234-5211

All testing are performed in Semi-anechoic chambers conforming to the site attenuation

Characteristics defined by ANSI C63.4, CISPR 22, 16-1 and 16-2 and Shielded rooms.

CSQAL is operated as testing laboratory in accordance with the requirements of ISO/IEC 17025:2005.

3. Test Setup configuration

3.1 Test Peripherals

The peripherals which were interconnected to the EUT during the test are as follows:

Item	Model No.	Serial No.	Manufacturer	Note
LCD Monitor	LS20C300	-	Samsung	EUT
Adaptor	A2514_DPN	CN07BN4400591BSK28CB6E165	Samsung	
PC	DM-V200-PA15	ZLPZ9WAZ500828F	Samsung	-
Printer	ML-2545/XAA	Z6FJBACB6000011N	Samsung	-
USB Keyboard	SK-8185	OY526K	Dell	-
USB Mouse	MOC5UO	J0F0217Q	Dell	-

3.2 EUT operating mode(s)

To achieve compliance applied standard specification, the following mode(s) were made during compliance testing:

Operating Mode 1	VGA IN
------------------	--------

3.3 Details of Sampling

Customer selected, single unit.

3.4 Cable description

The type(s) of cables which were connected to the ports (of the EUT) are as follows:

No	Connect Cable	Length [m]	Ferrite core [Y/N]	Remark
1	VGA in	1.5	Y	To PC
2	POWER	1.5	N	FOR EUT

3.5 EUT Description

The following features describe EUT represented by this report:

Model Name: LS20C300

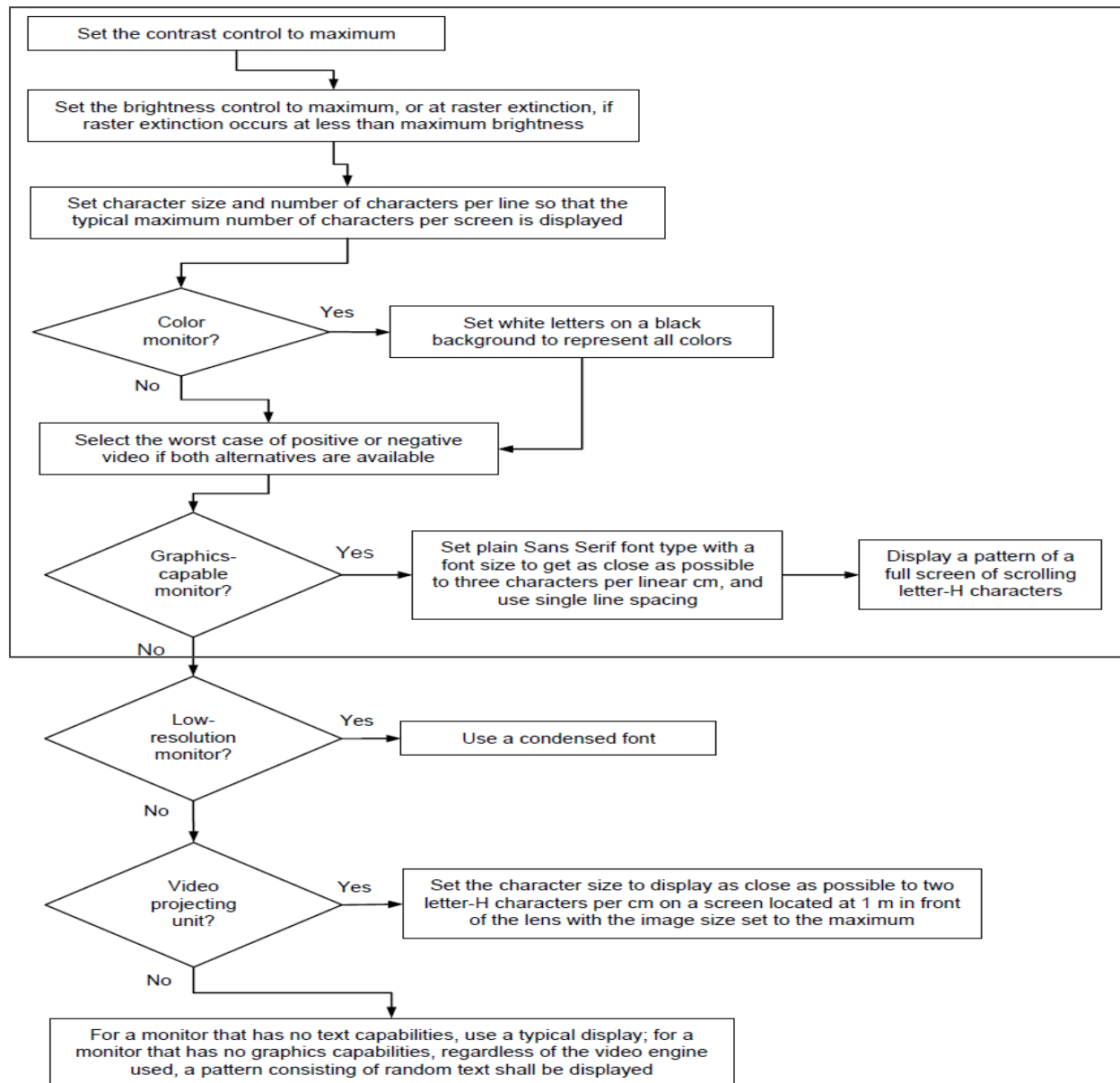
General	
Model Name	LS20C300
LCD Panel	
Size	19.5 inch (49cm)
Display area	432.(H) x 239.76(V)
Pixel Pitch(mm)	0.27(H) x 0.27(W)
Synchronization	
Horizontal	30~81kHz
Vertical	56~75Hz
Display Color	
16.7M	
Resolution	
Optimum resolution	1600x900 @ 60Hz
Maximum resolution	1600x900 @ 60Hz
Input Signal, Terminated	
RGB Analog	
0.7 Vp-p ± 5%	
separate H/V sync, Composite, SOG	
TTL level (V high ≥ 2.0V, V low ≤ 0.8V)	
Maximum Pixel Clock	
85MHz (Analog)	
Power Supply	
This product supports 100-240 V. Since the standard voltage may differ from country to country, please check the label on the back of the product.	
Signal Cable	
15pin-to-15pin D-sub cable, Detachable	
Dimensions (WxHxD)/ Weight	
Operating	Operating Temperature : 50°F ~ 104°F (10°C ~ 40°C) Humidity : 10% ~ 80%, non-condensing
Storage	Storage Temperature : -4°F ~ 113°F (-20°C ~ 45°C) Humidity : 5% ~ 95%, non-condensing

Display Mode		표시 형식	Horizontal Frequency (kHz)	Vertical Frequency (Hz)	Pixel Clock (MHz)	Sync Polarity (H/V)
IBM	720 x 400	70Hz	31.469	70.087	28.322	-/+
VESA DMT	640 x 480	60Hz	31.469	59.940	25.175	-/-
MAC	640 x 480	67Hz	35.000	66.667	30.240	-/-
VESA DMT	640 x 480	72Hz	37.861	72.809	31.500	-/-
VESA DMT	640 x 480	75Hz	37.500	75.000	31.500	-/-
VESA DMT	800 x 600	56Hz	35.156	56.250	36.000	+/+
VESA DMT	800 x 600	60Hz	37.879	60.317	40.000	+/+
VESA DMT	800 x 600	72Hz	48.077	72.188	50.000	+/+
VESA DMT	800 x 600	75Hz	46.875	75.000	49.500	+/+
MAC	832 x 624	75Hz	49.726	74.551	57.284	-/-
VESA DMT	1024 x 768	60Hz	48.363	60.004	65.000	-/-
VESA DMT	1024 x 768	70Hz	56.476	70.069	75.000	-/-
VESA DMT	1024 x 768	75Hz	60.023	75.029	78.750	+/+
VESA DMT	1152 x 864	75Hz	67.500	75.000	108.000	+/+
MAC	1152 x 870	75Hz	68.681	75.062	100.000	-/-
VESA DMT	1280 x 720	60Hz	45.000	60.000	74.250	+/+
VESA DMT	1280 x 800	60Hz	49.702	59.810	83.500	-/+
VESA DMT	1440 x 900	60Hz	55.935	59.887	106.500	-/+
VESA DMT	1440 x 900	75Hz	70.635	74.984	136.750	-/+
VESA DMT	1600 x 900RE	60Hz	60.000	60.000	108.000	+/+

3.6 Description of the EUT exercising method

The EUT exercise program used during EMI testing was CSQAL standardized test program for MS Windows. The program repetitively sends a screen of H – Character to the display. Connect video output of computer on EUT's PC IN (D-sub),HDMI port and scrolled H – character continuously on EUT's screen.

The EUT system includes a monitor, the operational conditions shown as follows, within the selected area.



- Notes:**
1. Set the brightness control to maximum
 2. Set the contrast control to maximum
 3. Display a pattern of a full screen of scrolling letter-H characters with a font size to get as close as possible to three characters per linear cm and use single line spacing

3.7 Measurement uncertainty

Where relevant, the following measurement uncertainty levels have been estimated for tests performed on the apparatus: (According to CISPR 16-4 and UKAS Lab 34.)

Test type			Measurement uncertainty (C.L. 95 %, k = 2)
Disturbance voltage at the mains terminals			2.8 dB
Radiated Disturbance	4.96 dB	30 MHz - 1 GHz	4.05 dB
	4.62 dB	30 MHz - 1 GHz	4.88 dB
	3.36 dB	1GHz - 6 GHz	3.36 dB
	3.5 %	1GHz - 6 GHz	3.36 dB

Power : AC110V 60Hz

4. Results of individual test

4.1 Conducted disturbance

Both conducted lines are measured in Quasi-Peak and Average mode, including the worst-case data points for each tested configuration.

The EUT measured in accordance with the methods described in standards.

Limits for conducted disturbance at the mains ports of class B ITE

Frequency range Limits MHz	Limits dB(μ V)	
	Quasi-peak	Average
0,15 to 0,50	66 to 56	56 to 46
0,50 to 5	56	46
5 to 30	60	50

Note 1: 1 μ V is regarded as 0 dB.
 Note 2: The limits shall decrease linearly with the logarithm of the frequency in the range 150 – 500 kHz.
 Note 3: If the average limit is met in the measurement with quasi-peak detector, the measurement with average detector is unnecessary.
 Note 4: The lower limit shall apply at the transition frequency.

If the reading on the measuring receiver shows fluctuations close to the limit, the reading shall be observed for at least 15 seconds at each measurement frequency, the highest reading shall be recorded, with the exception of any brief isolated high reading (which shall be ignored).

4.1.1 Test instrumentation

Test instrumentation used in the Conducted disturbance test was as follows:

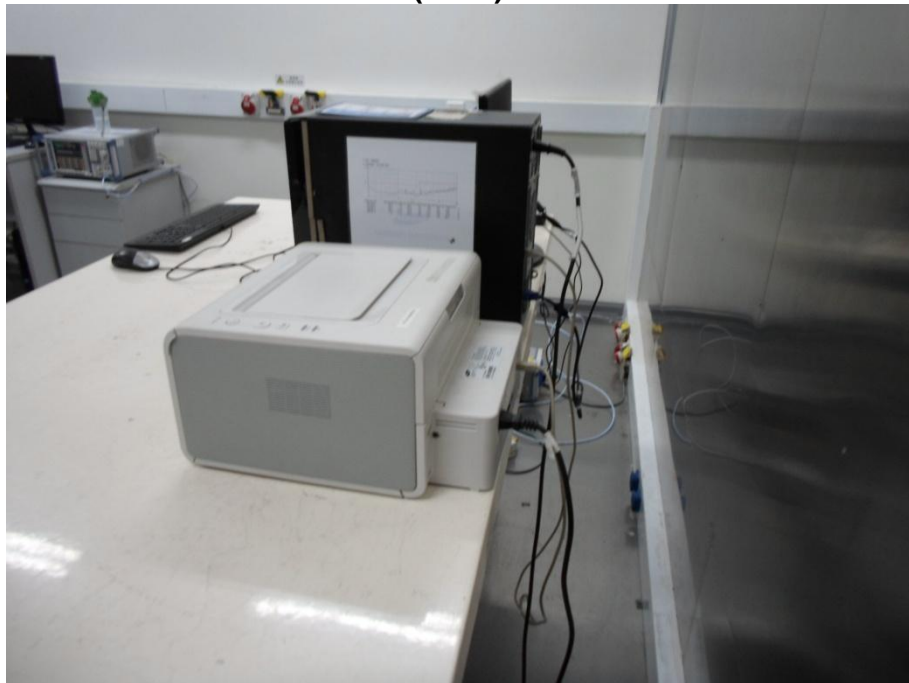
Test instrumentation	Model name	Manufacturer	Serial or Firmware (No./Ver.)	Calibration	
				Date	Interval (Month)
Test Software	EP5CE	TOYO	V 4.7.10	N/A	N/A
Measuring receiver	ESCI	R&S	101027	2012.03.02	12
Artificial mains network	ENV216	R&S	101122	2012.08.23	12
Artificial mains network	ENV216	R&S	101059	2012.08.23	12
ISN	ISN T800	TESEQ	28602	2012.08.23	12
ISN	ISN T8-CAT6	TESEQ	27286	2012.03.02	12

4.1.2 Photograph of the test Configuration

(Front)



(Rear)



4.1.3 Test results

Test date	2013.01.21		Test engineer		Hesong Jin	
Climate condition	Ambient temperature	23 °C	Relative humidity	24%	Atmospheric pressure	101.4 kPa
Test place	Shielded Room #2					

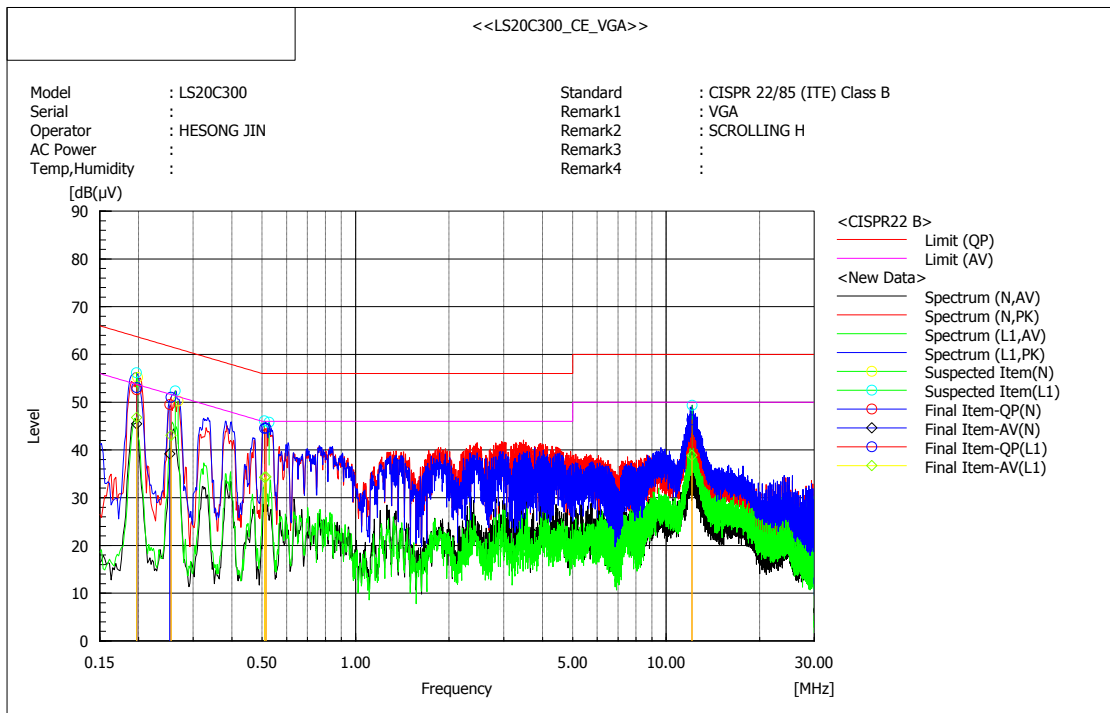
4.1.4 Test data

■ Operating Mode: VGA IN

Set the brightness control to maximum

Set the contrast control to maximum

Scan three resolutions (800*600@60Hz, 1024*768@60Hz, 1600*900@60Hz), then choose the worst one (1600*900@60Hz) for final evaluation.



Final Result

--- N Phase ---

No.	Frequency [MHz]	Reading		c. f [dB]	Result		Limit		Margin	
		QP [dB(μV)]	AV [dB(μV)]		QP [dB(μV)]	AV [dB(μV)]	QP [dB(μV)]	AV [dB(μV)]	QP [dB(μV)]	AV [dB(μV)]
1	0.19738	42.9	35.7	9.7	52.6	45.4	63.7	53.7	11.1	8.3
2	0.2523	39.8	29.5	9.7	49.5	39.2	61.7	51.7	12.2	12.5

--- L1 Phase ---

No.	Frequency [MHz]	Reading		c. f [dB]	Result		Limit		Margin	
		QP [dB(μV)]	AV [dB(μV)]		QP [dB(μV)]	AV [dB(μV)]	QP [dB(μV)]	AV [dB(μV)]	QP [dB(μV)]	AV [dB(μV)]
1	0.19726	43.4	37.1	9.7	53.1	46.8	63.7	53.7	10.6	6.9
2	0.25461	41.3	33.3	9.7	51.0	43.0	61.6	51.6	10.6	8.6
3	0.50961	34.8	24.5	9.7	44.5	34.2	56.0	46.0	11.5	11.8
4	0.51446	34.9	24.6	9.7	44.6	34.3	56.0	46.0	11.4	11.7
5	12.11916	36.4	29.0	9.9	46.3	38.9	60.0	50.0	13.7	11.1

Scan three resolutions (800*600@60Hz, 1024*768@60Hz, 1600*900@60Hz), then choose the worst one (1600*900@60Hz) for final evaluation.

Note) Level (Quasi-Peak and/or Average) = Meter Reading (Quasi-Peak and/or Average) + Factor (LISN Insertion Loss + Cable Loss)
 Margin = Limit – Level (Quasi-Peak and/or Average)

4.2 Radiated disturbance

Of those disturbances above ($L - 20\text{dB}$), where L is the limit level in logarithmic units, record at least the disturbance levels and the frequencies of the six highest disturbances.

The following data lists the significant emission frequencies, measured levels, correction factors (for antenna and cables), orientation of table, polarization and height of antenna, the corrected reading, the limit, and the amount of margin. All measurements were taken utilizing quasi-peak detection unless stated otherwise.

Measurements were performed at an antenna to EUT distance of 3 meters and elevated between 1 and 4 meters. Both vertical and horizontal antenna polarizations were measured.

Above 1GHz, peak detector function mode was used with resolution bandwidth of 1 MHz and a video bandwidth of 1 MHz. If the peak measured value complies with the average limit, it is unnecessary to perform an average measurement.

Except for Class A digital devices, the field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values:

Frequency range Limits MHz	Quasi-peak Limits (microvolts/meter)
	Class B
30 to 88	100
88 to 216	150
216 to 960	200
Above 960	500

Note 1: The lower limit shall apply at the transition frequency.
 Note 2: Additional provisions may be required for cases where interference occurs.
 Note 3: 1 $\mu\text{V}/\text{m}$ is regarded as 0 dB.

Measurements above 1GHz were performed at an antenna to EUT distance of 3 meters and elevated 1 to 4 meters in FAC. Both vertical and horizontal antenna polarizations were measured.

The test is performed in a semi-anechoic chamber, use of absorbing material to cover part of the metal ground plane, the dimension of the absorbing material is: 3 x 3 x 0.3 m (W x D x H)

Limits for radiated disturbance of ITE at a measuring distance of 3 m

Frequency range Limits MHz	Class A		Class B	
	Peak dB($\mu\text{V}/\text{m}$)	Average dB($\mu\text{V}/\text{m}$)	Peak dB($\mu\text{V}/\text{m}$)	Average dB($\mu\text{V}/\text{m}$)
1000 to 3000	76	56	70	50
3000 to 6000	80	60	74	54

Note 1: The lower limit shall apply at the transition frequency.

4.2.1 Test instrumentation

Test instrumentation used in the Radiated disturbance was as follows:

30MHz~1GHz

Test instrumentation	Model name	Manufacturer	Serial or Firmware (No./Ver.)	Calibration	
				Date	Interval (Month)
Test Software	EP5/RE	TOYO	V 4.7.10	N/A	N/A
Bi-con Antenna	CBL6112D	SCHAFFNER	29069	2011.04.04	24
EMI Receiver	ESCI	R&S	101026	2012.03.02	12
AMPLIFIER	310N	SONOMA	300911	2012.08.23	12
Ant Mast	MA4000	INN CO	-	N/A	N/A
Mast Controller	CO2000	INN CO	-	N/A	N/A
RF Selector	NS4900N	TOYO	-	N/A	N/A

1GHz-2GHz

Test instrumentation	Model name	Manufacturer	Serial or Firmware (No./Ver.)	Calibration	
				Date	Interval (Month)
Test Software	e3	AUDIX	6.110709d	N/A	N/A
Broad-Band Horn Antenna	BBHA9120B	Schwarzbeck	519	2011.04.05	24
EMI Receiver	ESU26	R&S	100243	2012.03.02	12
AMPLIFIER	AMF-4D-00500800-18-13P	TOYO	0934	2012.08.23	12
Ant Mast	AUDIX	AUDIX	-	N/A	N/A

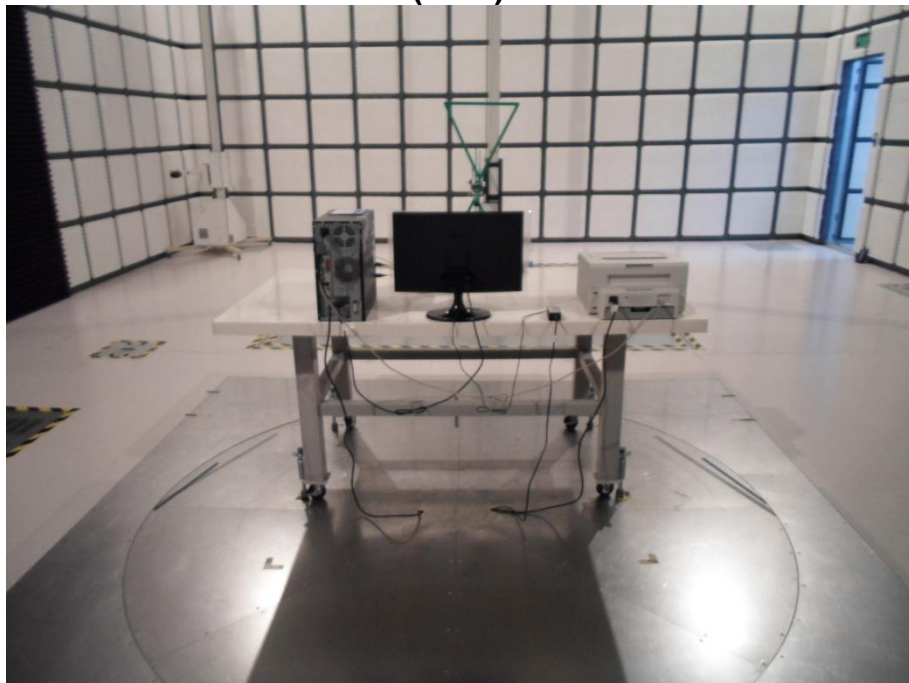
4.2.2 Photograph of the test Configuration

30MHz~1GHz

(Front)

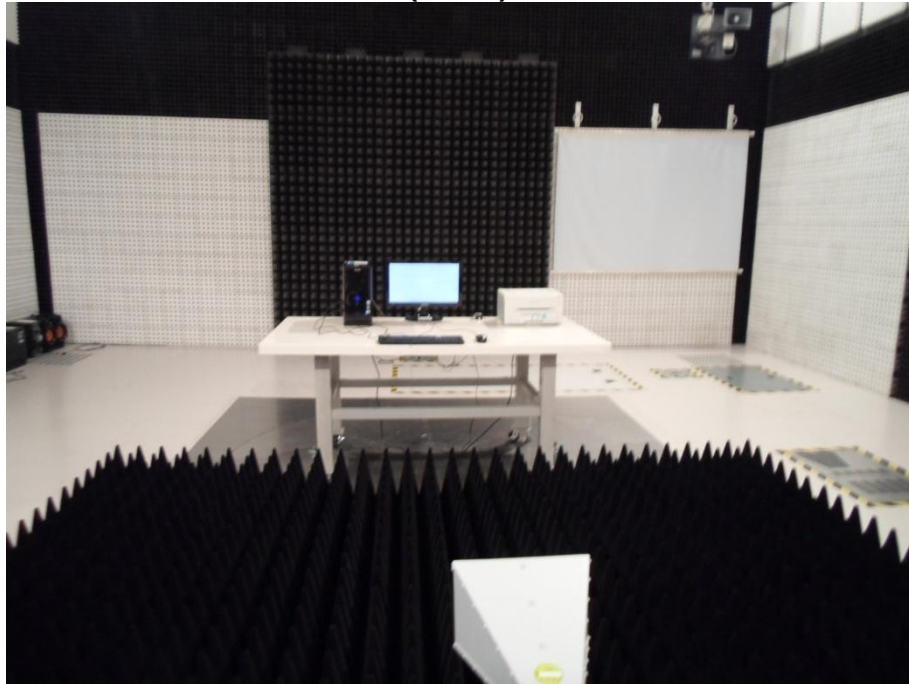


(Rear)

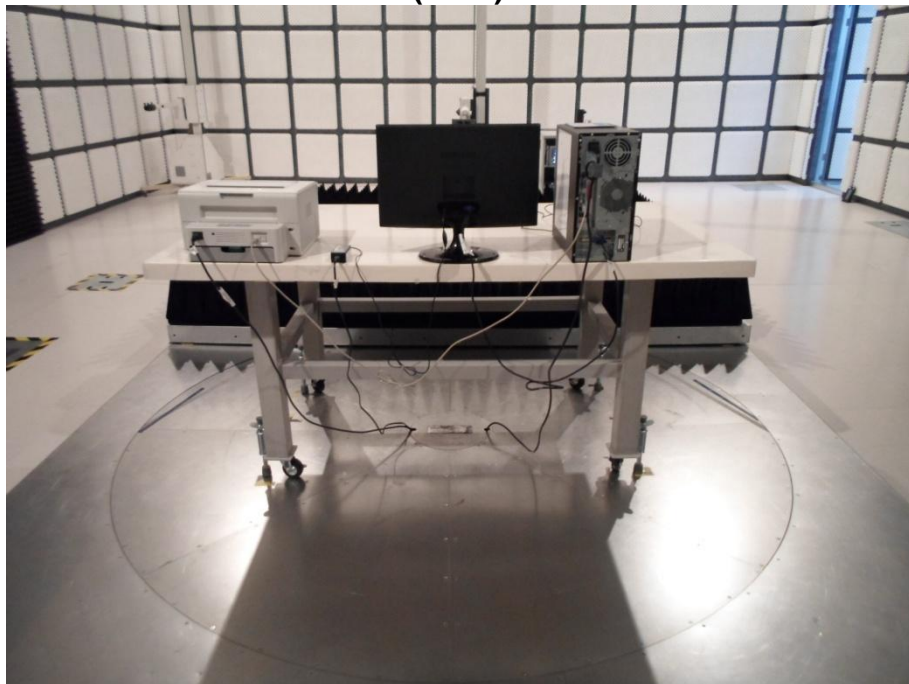


1GHz-2GHz

(Front)



(Rear)



4.2.3 Test results

30MHz~1GHz

Test date	2013.01.21		Test engineer		Hesong Jin	
Climate condition	Ambient temperature	23 °C	Relative humidity	24 %	Atmospheric pressure	101.5 kPa
Test place	3m Semi-Anechoic Chamber					

■ Operating Mode: D-Sub (PC Video IN or Analog) IN Display

Set the brightness control to maximum

Set the contrast control to maximum

Scan three resolutions (800*600@60Hz, 1024*768@60Hz, 1600*900@60Hz), then choose the worst one (1600*900@60Hz) for final evaluation.

1GHz-2GHz

Test date	2013.01.21		Test engineer		Hesong Jin	
Climate condition	Ambient temperature	22 °C	Relative humidity	25%	Atmospheric pressure	101.5 kPa
Test place	3m Semi-Anechoic Chamber					

■ Operating Mode: D-Sub (PC Video IN or Analog) IN Display

Set the brightness control to maximum

Set the contrast control to maximum

Scan three resolutions (800*600@60Hz, 1024*768@60Hz, 1600*900@60Hz), then choose the worst one (1600*900@60Hz) for final evaluation.

Appendix A – EUT photography

(Front)



(Rear)



(Left side)



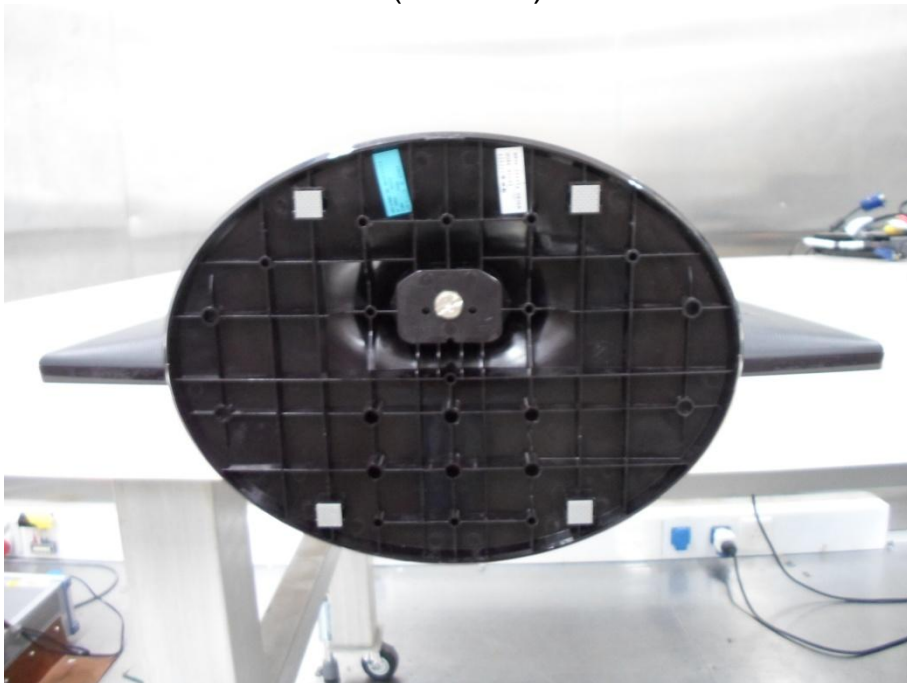
(Right side)



(Above)



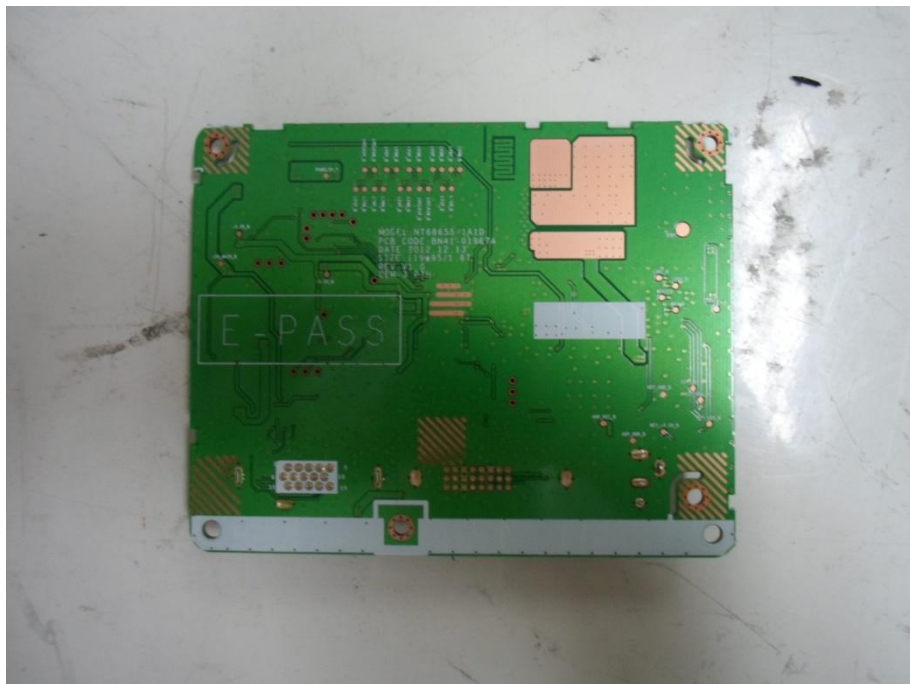
(Bottom)



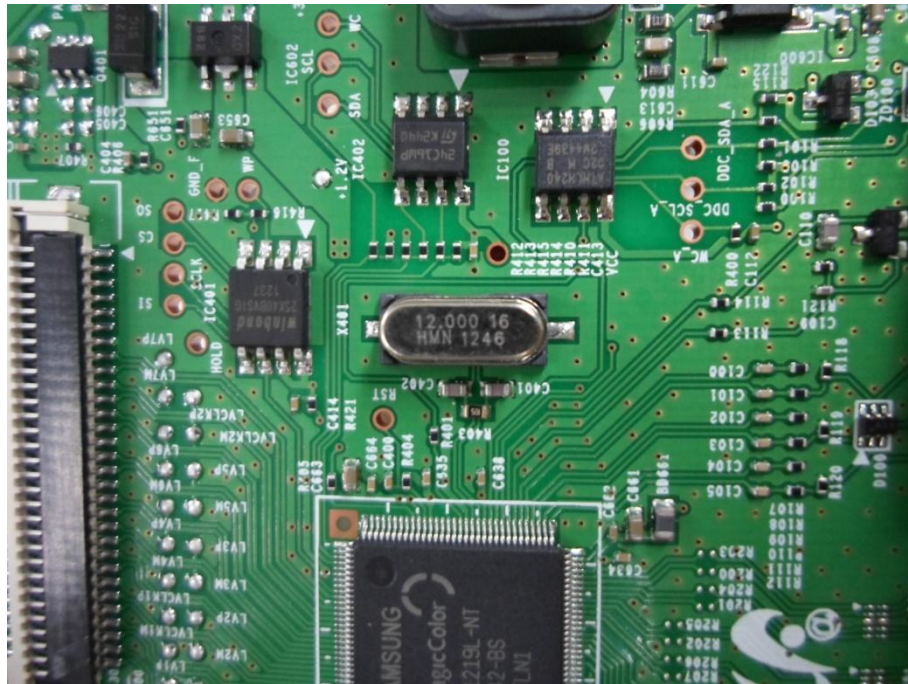
(Panel)



(MAIN Board)



(Crystal)



(Adaptor)

